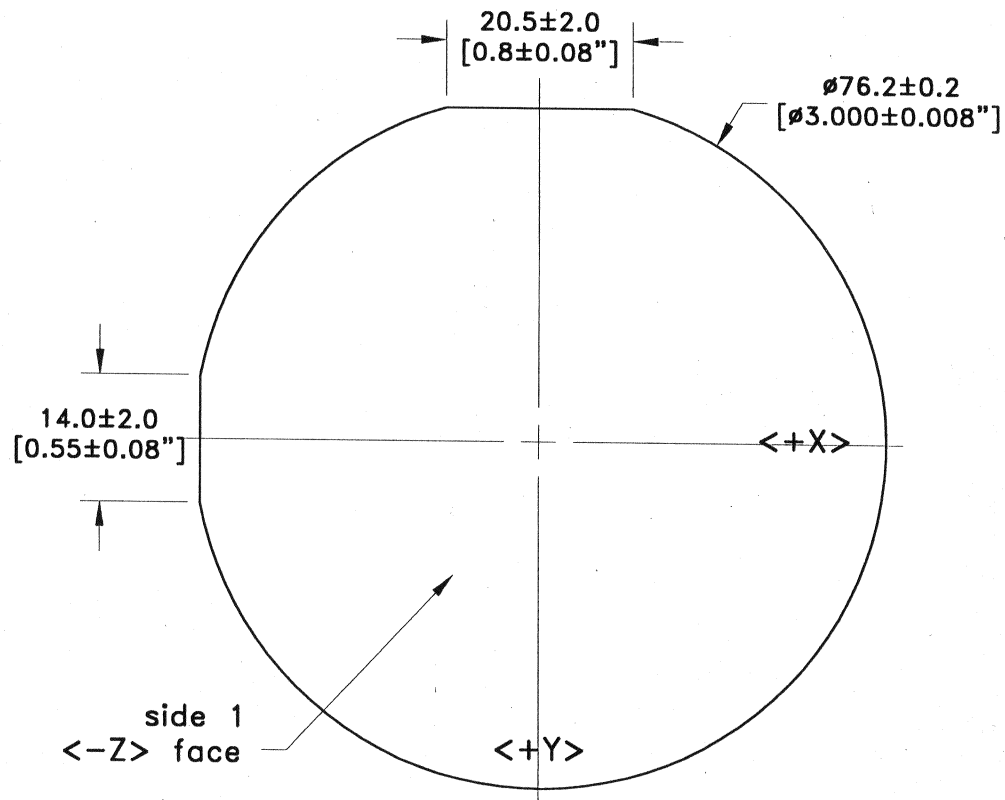


Notes:

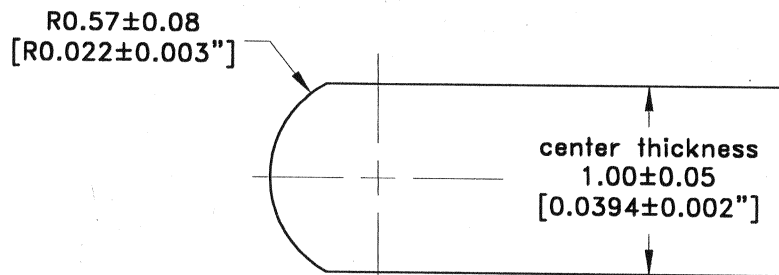
- 1.0 Material
Lithium Niobate, optical grade
- 2.0 Orientations
 - 2.1 Wafer surface is normal to $\langle Z \rangle \pm 0.3^\circ$
 - 2.2 Flats
 - 2.2.1 Primary flat is normal to $\langle -Y \rangle \pm 0.3^\circ$.
 - 2.2.2 Secondary flat is $90^\circ \pm 1^\circ$ counter clockwise from the primary flat when viewing the $\langle -Z \rangle$ face.
- 3.0 Edge
 - 3.1 All edges rounded with $R0.57 \pm 0.08\text{mm}$.
 - 3.2 No chips greater than 0.5mm in penetration and 1.0mm in length.
- 4.0 Surfaces
 - 4.1 Side 1 $\langle -Z \rangle$ face
Polished, 10-5 scratch-dig with 1mm edge exclusion. No pits or scratches visible with reflected light and unaided eye.
 - 4.2 Side 2 $\langle +Z \rangle$ face
Polished, 60-30 scratch-dig with 1mm edge exclusion. Light pits and scratches visible with reflected light and unaided eye.
- 5.0 Flatness (3mm edge exclusion)
 - 5.1 Warp $< 50\mu\text{m}$
 - 5.2 TTV $< 10\mu\text{m}$




DOCUMENT

AUG 01 2002

CONTROL



Wafer Edge Detail, 25X

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Material: Lithium Niobate	DR. Igordon	07-17-02	 Crystal Technology, Inc. An EPCOS Company
Unless otherwise specified, dimensions in mm	CHK. <i>Blundell</i>	7-18-02	
Tolerances	APPD. <i>Blundell</i>	7/18/02	Wafer Code: LNI0 76.2ø x 1.0mm, -Z Po/Po, -Y and -X FLT
Inches	Millimeters	Customer Approval:	Size: A Dwg. No: 99-60011-01 Rev: B
X ± 0.1 .XX ± 0.01 .XXX ± 0.005 .XXXX ± 0.0020	X ± 0.5 X ± 0.25 .XX ± 0.1 .XXX ± 0.05	DO NOT SCALE DRAWING	Scale: 1.2:1 Sheet 1 of 1
Angles ± 0.5°			